


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590632	<b>Applicant(s)/Patent Under Reexamination</b>  JENSEN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/15/2008	/YJK/
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<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/Young J Kim/ Primary Examiner.Art Unit 1637
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